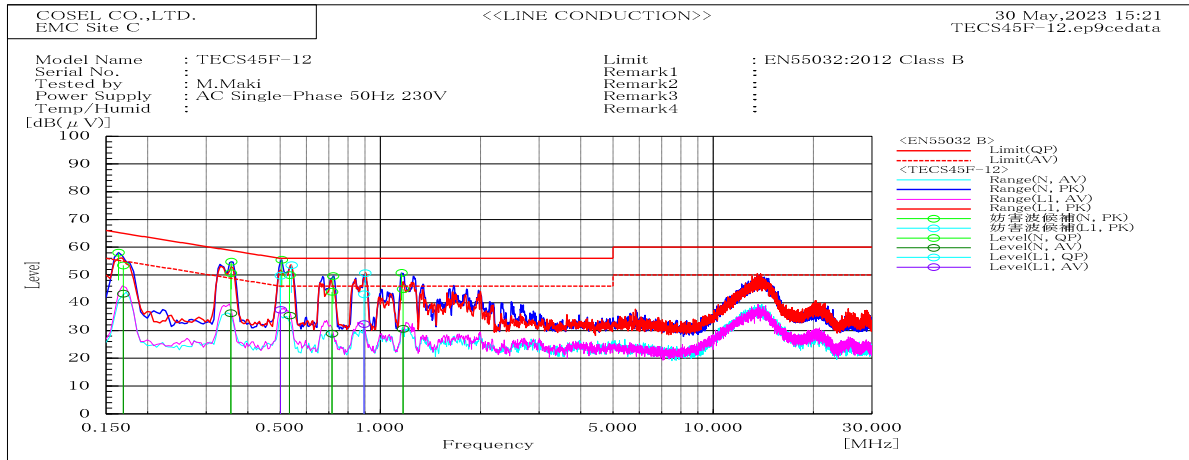
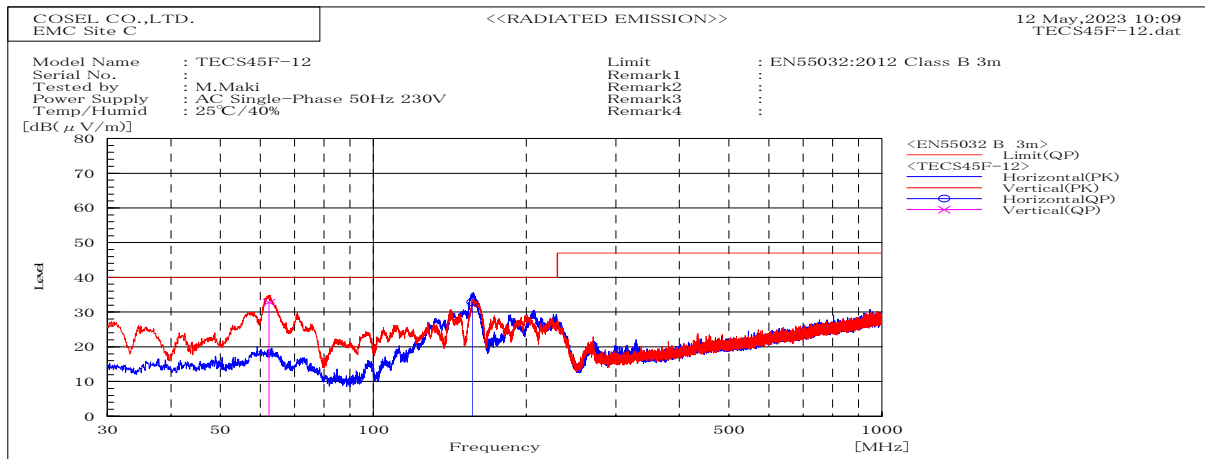


DATA SHEET		Date	12-Oct-23
Model	TECS45F-12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Maki



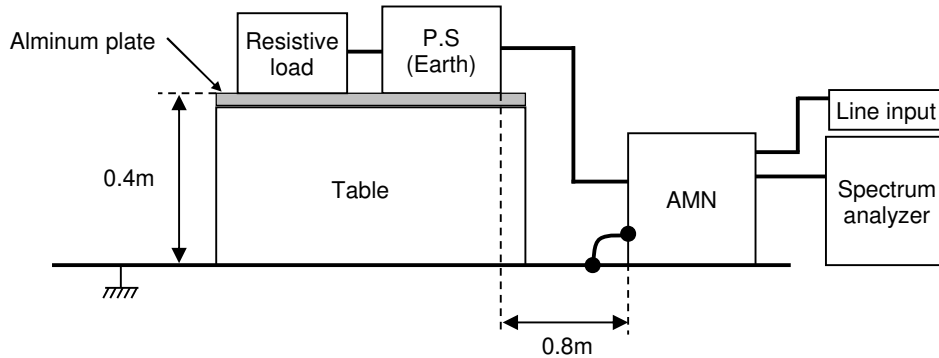
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.169	N	53.5	43.3	65	55	11.5	11.7	Pass	
0.356	N	50.7	36.2	58.8	48.8	8.1	12.6	Pass	
0.534	N	50	35.4	56	46	6	10.6	Pass	
0.716	N	43.9	28.9	56	46	12.1	17.1	Pass	
1.17	N	44.9	30.6	56	46	11.1	15.4	Pass	
0.502	L1	49.8	37.5	56	46	6.2	8.5	Pass	
0.894	L1	43.1	32.3	56	46	12.9	13.7	Pass	



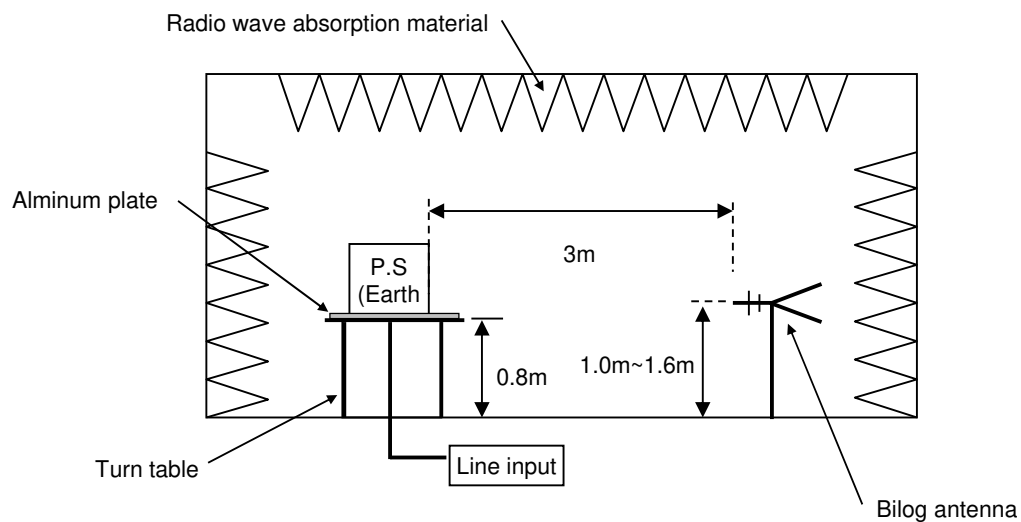
Frequency MHz	Polarization	Stability	Level	Limit	MARGIN	Pass/Fail	Height cm	Angle deg	Remark
			dB(μV/m) QP	dB(μV/m) QP	dB QP				
156.629	H	Stable	32.8	40	7.2	Pass	190.3	348.2	
62.397	V	Stable	32.8	40	7.2	Pass	100	0	

DATA SHEET		Date	12-Oct-23
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	M.Maki

1. Line conduction



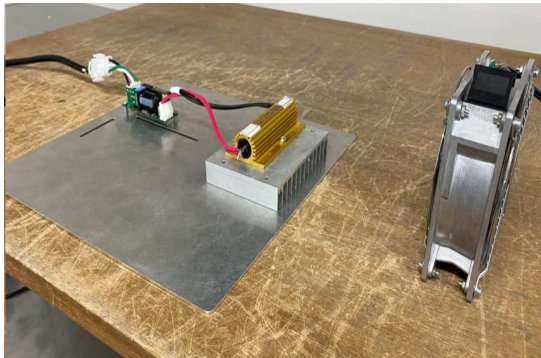
2. Radiated emission



Conditions

Test : EMI
Model Nam: TECS45F-12

1.LINE CONDUCTION



2.RADIATED EMISSION

